

Advance Information

MPC7441EC/D
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MPC7441
RISC Microprocessor
Hardware Specifications



The MPC7441 is a reduced instruction set computing (RISC) microprocessor that implements the PowerPC instruction set architecture. This document describes pertinent electrical and physical characteristics of the MPC7441. For functional characteristics of the processor, refer to the *MPC7450 RISC Microprocessor Family User's Manual*.

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1.1 Overview

The MPC7441 is the third implementation of the fourth generation (G4) microprocessors from Motorola. The MPC7441 implements the full PowerPC 32-bit architecture and is targeted at networking and computing systems applications. The MPC7441 consists of a processor core and a 256-Kbyte L2.

Figure 1 shows a block diagram of the MPC7441. The core is a high-performance superscalar design supporting a double-precision floating-point unit and a SIMD multimedia unit. The memory storage subsystem supports the MPX bus interface to main memory and other system resources.

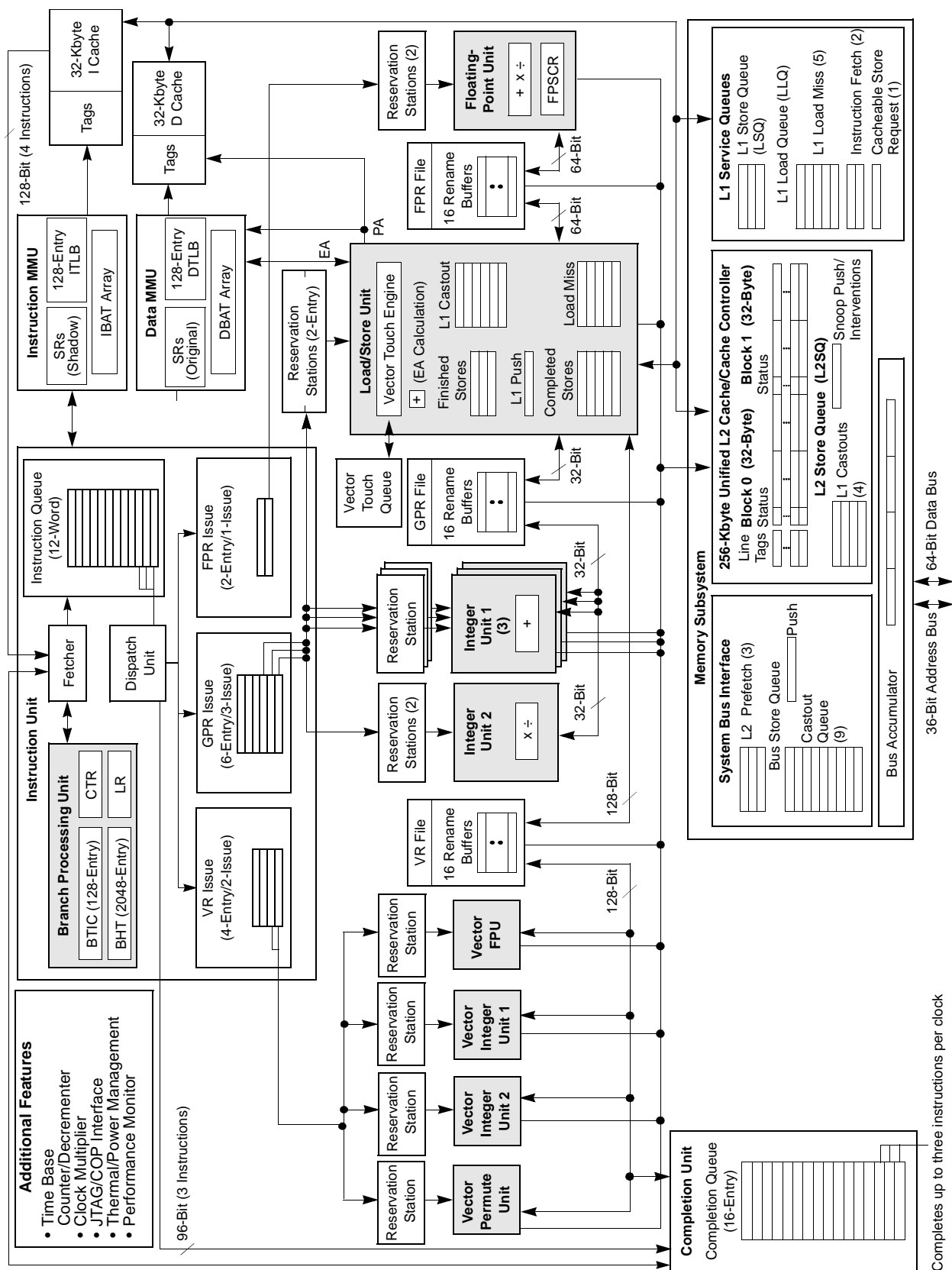


Figure 1. MPC7441 Block Diagram

1.2 Features

This section summarizes features of the MPC7441 implementation of the PowerPC architecture. Major features of the MPC7441 are as follows:

Major features of the MPC7441 are as follows:

- High-performance, superscalar microprocessor
 - As many as 4 instructions can be fetched from the instruction cache at a time
 - As many as 3 instructions can be dispatched to the issue queues at a time
 - As many as 12 instructions can be in the instruction queue (IQ)
 - As many as 16 instructions can be at some stage of execution simultaneously
 - Single-cycle execution for most instructions
 - One instruction per clock cycle throughput for most instructions
 - Seven-stage pipeline control
- Eleven independent execution units and three register files
 - Branch processing unit (BPU) features static and dynamic branch prediction
 - 128-entry (32-set, four-way set-associative) branch target instruction cache (BTIC), a cache of branch instructions that have been encountered in branch/loop code sequences. If a target instruction is in the BTIC, it is fetched into the instruction queue a cycle sooner than it can be made available from the instruction cache. Typically, a fetch that hits the BTIC provides the first four instructions in the target stream.
 - 2048-entry branch history table (BHT) with two bits per entry for four levels of prediction—
not-taken, strongly not-taken, taken, strongly taken
 - Up to three outstanding speculative branches
 - Branch instructions that do not update the count register (CTR) or link register (LR) are often removed from the instruction stream.
 - 8-entry link register stack to predict the target address of Branch Conditional to Link Register (**bclr**) instructions.
 - Four integer units (IUs) that share 32 GPRs for integer operands
 - Three identical IUs (IU1a, IU1b, and IU1c) can execute all integer instructions except multiply, divide, and move to/from special-purpose register instructions.
 - IU2 executes miscellaneous instructions including the CR logical operations, integer multiplication and division instructions, and move to/from special-purpose register instructions.
 - Five-stage FPU and a 32-entry FPR file
 - Fully IEEE 754-1985-compliant FPU for both single- and double-precision operations
 - Supports non-IEEE mode for time-critical operations
 - Hardware support for denormalized numbers
 - Thirty-two 64-bit FPRs for single- or double-precision operands
 - Four vector units and 32-entry vector register file (VRs)
 - Vector permute unit (VPU)

Features

- Vector integer unit 1 (VIU1) handles short-latency AltiVec integer instructions, such as vector add instructions (**vaddsbs**, **vaddshs**, and **vaddsws**, for example)
- Vector integer unit 2 (VIU2) handles longer -latency AltiVec integer instructions, such as vector multiply add instructions (**vmhaddshs**, **vmhraddshs**, and **vmladduhm**, for example).
- Vector floating-point unit (VFPU)
- Three-stage load/store unit (LSU)
 - Supports integer, floating-point and vector instruction load/store traffic
 - Four-entry vector touch queue (VTQ) supports all four architected AltiVec data stream operations
 - Three-cycle GPR and AltiVec load latency (byte, half-word, word, vector) with 1-cycle throughput
 - Four-cycle FPR load latency (single, double) with 1-cycle throughput
 - No additional delay for misaligned access within double-word boundary
 - Dedicated adder calculates effective addresses (EAs)
 - Supports store gathering
 - Performs alignment, normalization, and precision conversion for floating-point data
 - Executes cache control and TLB instructions
 - Performs alignment, zero padding, and sign extension for integer data
 - Supports hits under misses (multiple outstanding misses)
 - Supports both big- and little-endian modes, including misaligned little-endian accesses
- Three issue queues FIQ, VIQ, and GIQ can accept as many as one, two, and three instructions, respectively, in a cycle. Instruction dispatch requires the following:
 - Instructions can be dispatched only from the three lowest IQ entries—IQ0, IQ1, and IQ2.
 - A maximum of three instructions can be dispatched to the issue queues per clock cycle.
 - Space must be available in the CQ for an instruction to dispatch (this includes instructions that are assigned a space in the CQ but not in an issue queue).
- Rename buffers
 - 16 GPR rename buffers
 - 16 FPR rename buffers
 - 16 VR rename buffers
- Dispatch unit
 - The decode/dispatch stage fully decodes each instruction.
- Completion unit
 - The completion unit retires an instruction from the 16-entry completion queue (CQ) when all instructions ahead of it have been completed, the instruction has finished execution, and no exceptions are pending.
 - Guarantees sequential programming model (precise exception model)
 - Monitors all dispatched instructions and retires them in order

- Tracks unresolved branches and flushes instructions after a mispredicted branch
- Retires as many as three instructions per clock cycle
- Separate on-chip L1 instruction and data caches (Harvard architecture)
 - 32-Kbyte, eight-way set-associative instruction and data caches
 - Pseudo least-recently-used (PLRU) replacement algorithm
 - 32-byte (eight-word) L1 cache block
 - Physically indexed/physical tags
 - Cache write-back or write-through operation programmable on a per-page or per-block basis
 - Instruction cache can provide four instructions per clock cycle; data cache can provide four words per clock cycle
 - Caches can be disabled in software
 - Caches can be locked in software
 - MESI data cache coherency maintained in hardware
 - Separate copy of data cache tags for efficient snooping
 - Parity support on cache and tags
 - No snooping of instruction cache except for **icbi** instruction
 - Data cache supports AltiVec LRU and transient instructions
 - Critical double- and/or quad-word forwarding is performed as needed. Critical quad-word forwarding is used for AltiVec loads and instruction fetches. Other accesses use critical double-word forwarding.
- Level 2 (L2) cache interface
 - On-chip, 256-Kbyte, 8-way set associative unified instruction and data cache
 - Fully pipelined to provide 32 bytes per clock cycle to the L1 caches
 - A total 9-cycle load latency for an L1 data cache miss that hits in L2
 - Pseudo least-recently-used (PLRU) replacement algorithm
 - Cache write-back or write-through operation programmable on a per-page or per-block basis
 - 64-byte, two-sectored line size
 - Parity support on cache
- Separate memory management units (MMUs) for instructions and data
 - 52-bit virtual address; 32- or 36-bit physical address
 - Address translation for 4-Kbyte pages, variable-sized blocks, and 256-Mbyte segments
 - Memory programmable as write-back/write-through, caching-inhibited/caching-allowed, and memory coherency enforced/memory coherency not enforced on a page or block basis
 - Separate IBATs and DBATs (four each) also defined as SPRs
 - Separate instruction and data translation lookaside buffers (TLBs)
 - Both TLBs are 128-entry, two-way set associative, and use LRU replacement algorithm
 - TLBs are hardware- or software-reloadable (that is, on a TLB miss a page table search is performed in hardware or by system software)

Features

- Efficient data flow
 - Although the VR/LSU interface is 128 bits, the L1/L2 bus interface allows up to 256 bits.
 - The L1 data cache is fully pipelined to provide 128 bits/cycle to or from the VRs
 - L2 cache is fully pipelined to provide 256 bits per processor clock cycle to the L1 cache.
 - As many as 8 outstanding, out-of-order, cache misses are allowed between the L1 data cache and L2 bus.
 - As many as 16 out-of-order transactions can be present on the MPX bus
 - Store merging for multiple store misses to the same line. Only coherency action taken (address-only) for store misses merged to all 32 bytes of a cache block (no data tenure needed).
 - Three-entry finished store queue and five-entry completed store queue between the LSU and the L1 data cache
 - Separate additional queues for efficient buffering of outbound data (such as cast outs and write through stores) from the L1 data cache and L2 cache
- Multiprocessing support features include the following:
 - Hardware-enforced, MESI cache coherency protocols for data cache
 - Load/store with reservation instruction pair for atomic memory references, semaphores, and other multiprocessor operations
- Power and thermal management
 - 1.5-V processor core
 - The following three power-saving modes are available to the system:
 - Nap—Instruction fetching is halted. Only those clocks for the thermal assist unit (TAU), time base, decremter, and JTAG logic remain running. The part goes into the doze state to snoop memory operations on the bus and then back to nap using a QREQ/QACK processor-system handshake protocol.
 - Sleep—Power consumption is further reduced by disabling bus snooping, leaving only the PLL in a locked and running state. All internal functional units are disabled.
 - Deep sleep—When the part is in the sleep state, the system can disable the PLL resulting. The system can then disable the SYSCLK source for greater system power savings. Power-on reset procedures for restarting and relocking the PLL must be followed on exiting the deep sleep state.
 - Thermal management facility provides software-controllable thermal management. Thermal management is performed through the use of three supervisor-level registers and an MPC7441-specific thermal management exception.
 - Instruction cache throttling provides control of instruction fetching to limit power consumption.
- Performance monitor can be used to help debug system designs and improve software efficiency.
- In-system testability and debugging features through JTAG boundary-scan capability
- Testability
 - LSSD scan design
 - IEEE 1149.1 JTAG interface
 - Array built-in self test (ABIST)—factory test only

- Reliability and serviceability
 - Parity checking on system bus
 - Parity checking on L1 and L2

1.3 Comparison with the MPC7400

Table 1 compares the key features of the MPC7441 with the key features of the earlier MPC7400. To achieve a higher frequency, the number of logic levels per cycle is reduced. Also, to achieve this higher frequency, the pipeline of the MPC7441 is extended (compared to the MPC7400), while maintaining the same level of performance as measured by the number of instructions executed per cycle (IPC).

Table 1. Microarchitecture Comparison

Microarchitectural Specs	MPC7441	MPC7400/MPC7410
Basic Pipeline Functions		
Logic Inversions per Cycle	18	28
Pipeline Stages up to Execute	5	3
Total Pipeline Stages (Minimum)	7	4
Pipeline Maximum Instruction Throughput	3 + Branch	2 + Branch
Pipeline Resources		
Instruction Buffer Size	12	6
Completion Buffer Size	16	8
Renames (Integer, Float, Vector)	16, 16, 16	6, 6, 6
Maximum Execution Throughput		
SFX	3	2
Vector	2 (Any 2 of 4 Units)	2 (Permute/Fixed)
Scalar Floating-Point	1	1
Out-of-Order Window Size in Execution Queues		
SFX Integer Units	1 Entry × 3 Queues	1 Entry × 2 Queues
Vector Units	In Order, 4 Queues	In Order, 2 Queues
Scalar Floating-Point Unit	In Order	In Order
Branch Processing Resources		
Prediction Structures	BTIC, BHT, Link Stack	BTIC, BHT
BTIC Size, Associativity	128-Entry, 4-Way	64-Entry, 4-Way
BHT Size	2K-Entry	512-Entry
Link Stack Depth	8	None
Unresolved Branches Supported	3	2
Branch Taken Penalty (BTIC Hit)	1	0
Minimum Misprediction Penalty	6	4

Table 1. Microarchitecture Comparison (continued)

Microarchitectural Specs	MPC7441	MPC7400/MPC7410
Execution Unit Timings (Latency-Throughput)		
Aligned Load (Integer, Float, Vector)	3-1, 4-1, 3-1	2-1, 2-1, 2-1
Misaligned Load (Integer, Float, Vector)	4-2, 5-2, 4-2	3-2, 3-2, 3-2
L1 Miss, L2 Hit Latency	6 (9)	9 (11) ¹
SFX (aDd Sub, Shift, Rot, Cmp, Logicals)	1-1	1-1
Integer Multiply (32×8 , 32×16 , 32×32)	3-1, 3-1, 4-2	2-1, 3-2, 5-4
Scalar Float	5-1	3-1
VSFX (Vector Simple)	1-1	1-1
VCFX (Vector Complex)	4-1	3-1
VFPU (Vector Float)	4-1	4-1
VPER (Vector Permute)	2-1	1-1
MMUs		
MMUs (Instruction and Data)	128-Entry, 2-Way	128-Entry, 2-Way
Tablewalk Mechanism	Hardware + Software	Hardware
L1 I Cache/D Cache Features		
Size	32K/32K	32K/32K
Associativity	8-Way	8-Way
Locking Granularity/Style	4-Kbyte/Way	Full Cache
Parity on I Cache	Word	None
Parity on D Cache	Byte	None
Number of D Cache Misses (Load/Store)	5/1	8 (Any Combination)
Data Stream Touch Engines	4 Streams	4 Streams
On-Chip Cache Features		
Cache Level	L2	None (Except L1)
Size/Associativity	256-Kbyte/8-Way	N/A
Access Width	256 Bits	N/A
Number of 32-Byte Sectors/Line	2	N/A
Parity	Byte	N/A
Off-Chip Cache Support		
Cache Level	N/A	L2
On-Chip Tag Logical Size	N/A	0.5MB, 1MB, 2MB
Associativity	N/A	2-Way
Number of 32-Byte Sectors/Line	N/A	1, 2, 4
Off-Chip Data SRAM Support	N/A	LW, PB2, PB3
Data Path Width	N/A	64

Table 1. Microarchitecture Comparison (continued)

Microarchitectural Specs	MPC7441	MPC7400/MPC7410
Direct Mapped SRAM Sizes	N/A	0.5 Mbyte, 1 Mbyte, 2 Mbytes
Parity	N/A	Byte

¹ Numbers in parentheses are for 2:1 SRAM.

1.4 General Parameters

The following list provides a summary of the general parameters of the MPC7441:

Technology	0.18 μ m CMOS, six-layer metal
Die size	8.69 mm \times 12.17 mm (106 mm ²)
Transistor count	33 million
Logic design	Fully static
Packages	MPC7441: Surface mount 360 ceramic ball grid array (CBGA)
Core power supply	1.5 V \pm 50 mV DC nominal
I/O power supply	1.8 V \pm 5% DC or 2.5 V \pm 5% DC

1.5 Electrical and Thermal Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC7441.

1.5.1 DC Electrical Characteristics

The tables in this section describe the MPC7441 DC electrical characteristics. Table 2 provides the absolute maximum ratings.

Table 2. Absolute Maximum Ratings¹

Characteristic		Symbol	Maximum Value	Unit	Notes
Core supply voltage		V _{DD}	−0.3 to 1.95	V	4
PLL supply voltage		AV _{DD}	−0.3 to 1.95	V	4
Processor bus supply voltage	BVSEL = 0	OV _{DD}	−0.3 to 1.95	V	3, 6
	BVSEL = $\overline{\text{HRESET}}$ or OV _{DD}	OV _{DD}	−0.3 to 2.7	V	3, 7
Input voltage	Processor bus	V _{in}	−0.3 to OV _{DD} + 0.3	V	2, 5
	JTAG signals	V _{in}	−0.3 to OV _{DD} + 0.3	V	

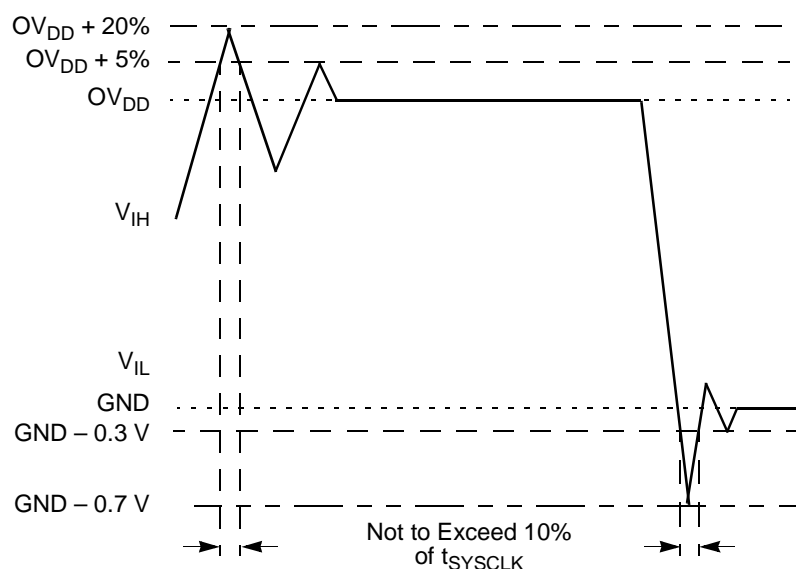
Table 2. Absolute Maximum Ratings¹ (continued)

Characteristic	Symbol	Maximum Value	Unit	Notes
Storage temperature range	T_{stg}	-55 to 150	°C	

Notes:

1. Functional and tested operating conditions are given in Table 4. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
2. **Caution:** V_{in} must not exceed OV_{DD} by more than 0.3 V at any time including during power-on reset.
3. **Caution:** OV_{DD} must not exceed V_{DD}/AV_{DD} by more than 2.0 V at any time including during power-on reset.
4. **Caution:** V_{DD}/AV_{DD} must not exceed OV_{DD} by more than 0.4 V at any time including during power-on reset.
5. V_{in} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.
6. BVSEL must be set to 0, such that the bus is in 1.8 V mode.
7. BVSEL must be set to HRESET or 1, such that the bus is in 2.5 V mode.

Figure 2 shows the undershoot and overshoot voltage on the MPC7441.

**Figure 2. Overshoot/Undershoot Voltage**

The MPC7441 provides several I/O voltages to support both compatibility with existing systems and migration to future systems. The MPC7441 core voltage must always be provided at nominal 1.5 V (see Table 4 for actual recommended core voltage). Voltage to the processor interface I/Os are provided through separate sets of supply pins and may be provided at the voltages shown in Table 3. The input voltage threshold for each bus is selected by sampling the state of the voltage select pins at the negation of the signal \overline{HRESET} . The output voltage will swing from GND to the maximum voltage applied to the OV_{DD} power pins.

Table 3. Input Threshold Voltage Setting

BVSEL Signal	Processor Bus Input Threshold is Relative to:	Notes
0	1.8 V	1, 4
$\overline{\text{HRESET}}$	Not Available	1, 3
$\overline{\text{HRESET}}$	2.5 V	1, 2
1	2.5 V	1

Notes:

1. **Caution:** The input threshold selection must agree with the $\text{OV}_{\text{DD}}/\text{GV}_{\text{DD}}$ voltages supplied. See notes in Table 2.
2. To select the 2.5-V threshold option for the processor bus, BVSEL should be tied to $\overline{\text{HRESET}}$ so that the two signals change state together. This is the preferred method for selecting this mode of operation.
3. $\overline{\text{HRESET}}$ is the inverse of $\overline{\text{HRESET}}$.
4. If used, pulldown resistors should be less than 250 Ω .

Table 4 provides the recommended operating conditions for the MPC7441.

Table 4. Recommended¹ Operating Conditions

Characteristic		Symbol	Recommended Value		Unit	Notes
			Min	Max		
Core supply voltage		V_{DD}	1.5 V \pm 50 mV		V	
PLL supply voltage		AV_{DD}	1.5 V \pm 50 mV		V	2
Processor bus supply voltage	BVSEL = 0	OV_{DD}	1.8 V \pm 5%		V	
	BVSEL = $\overline{\text{HRESET}}$ or OV_{DD}	OV_{DD}	2.5 V \pm 5%		V	
Input voltage	Processor bus	V_{in}	GND	OV_{DD}	V	
	JTAG signals	V_{in}	GND	OV_{DD}	V	
Die-junction temperature		T_{j}	0	105	$^{\circ}\text{C}$	

Notes:

1. These are the recommended and tested operating conditions. Proper device operation outside of these conditions is not guaranteed.
2. This voltage is the input to the filter discussed in Section 1.9.2, "PLL Power Supply Filtering" and not necessarily the voltage at the AV_{DD} pin which may be reduced from V_{DD} by the filter.

Table 5 provides the package thermal characteristics for the MPC7441.

Table 5. Package Thermal Characteristics

Characteristic	Symbol	Value	Rating
CBGA package thermal resistance, junction-to-case thermal resistance (typical)	θ_{JC}	<0.1	$^{\circ}\text{C}/\text{W}$
CBGA package thermal resistance, die junction-to-lead thermal resistance (typical)	θ_{JB}	2.2	$^{\circ}\text{C}/\text{W}$

Note: Refer to Section 1.9, "System Design Information," for more details about thermal management.

Electrical and Thermal Characteristics

Table 6 provides the DC electrical characteristics for the MPC7441.

Table 6. DC Electrical Specifications

At recommended operating conditions. See Table 4.

Characteristic		Nominal Bus Voltage ¹	Symbol	Min	Max	Unit	Notes
Input high voltage (all inputs except SYSCLK)		1.8	V_{IH}	$OV_{DD} \times 0.65$	$OV_{DD} + 0.3$	V	
		2.5	V_{IH}	1.7	$OV_{DD} + 0.3$	V	
Input low voltage (all inputs except SYSCLK)		1.8	V_{IL}	-0.3	$OV_{DD} \times 0.35$	V	
		2.5	V_{IL}	-0.3	0.7	V	
SYSCLK input high voltage		—	CV_{IH}	1.4	$OV_{DD} + 0.3$	V	
SYSCLK input low voltage		—	CV_{IL}	-0.3	0.4	V	
Input leakage current, $V_{in} = OV_{DD} + 0.3$ V		—	I_{in}	—	10	μ A	2, 3
High impedance (off-state) leakage current, $V_{in} = OV_{DD} + 0.3$ V		—	I_{TSI}	—	10	μ A	2, 3, 5
Output high voltage, $I_{OH} = -5$ mA		1.8	V_{OH}	$OV_{DD} - 0.45$	—	V	
		2.5	V_{OH}	1.7	—	V	
Output low voltage, $I_{OL} = 5$ mA		1.8	V_{OL}	—	0.45	V	
		2.5	V_{OL}	—	0.7	V	
Capacitance, $V_{in} = 0$ V, $f = 1$ MHz	All inputs	—	C_{in}	—	8.0	pF	4

Notes:

1. Nominal voltages; see Table 4 for recommended operating conditions.
2. For processor bus signals, the reference is OV_{DD} .
3. Excludes test signals and IEEE 1149.1 boundary scan (JTAG) signals.
4. Capacitance is periodically sampled rather than 100% tested.
5. The leakage is measured for nominal OV_{DD} and V_{DD} , or both OV_{DD} and V_{DD} must vary in the same direction (for example, both OV_{DD} and V_{DD} vary by either +5% or -5%).

Table 7 provides the power consumption for the MPC7441.

Table 7. Power Consumption for MPC7441

	Processor (CPU) Frequency		Unit	Notes
	600 MHz	700 MHz		
Full-Power Mode				
Typical	11.5	13.4	W	1, 3
Maximum	15.4	17.6	W	1, 2
Doze Mode				
Typical	—	—	W	1, 3, 4

Table 7. Power Consumption for MPC7441 (continued)

	Processor (CPU) Frequency		Unit	Notes
	600 MHz	700 MHz		
Nap Mode				
Typical	1.3	1.6	W	1, 3
Sleep Mode				
Typical	0.7	0.8	W	1, 3
Deep Sleep Mode (PLL Disabled)				
Typical	410	480	mW	1, 3

Notes:

1. These values apply for all valid processor bus ratios. The values do not include I/O supply power (OV_{DD}) or PLL supply power (AV_{DD}). OV_{DD} power is system dependent, but is typically <20% of V_{DD} power. Worst case power consumption for AV_{DD} < 3 mW.
2. Maximum power is measured at nominal V_{DD} (see Table 4) while running an entirely cache-resident, contrived sequence of instructions which keep the execution units, with or without AltiVec, maximally busy.
3. Typical power is an average value measured at the nominal recommended V_{DD} (see Table 4) in a system while running a typical code sequence.
4. Doze mode is not a user-definable state; it is an intermediate state between full-power and either nap or sleep mode. As a result, power consumption for this mode is not tested.

1.5.2 AC Electrical Characteristics

This section provides the AC electrical characteristics for the MPC7441. After fabrication, functional parts are sorted by maximum processor core frequency as shown in Section 1.5.2.1, “Clock AC Specifications,” and tested for conformance to the AC specifications for that frequency. The processor core frequency is determined by the bus (SYSCLK) frequency and the settings of the PLL_EXT and PLL_CFG[0:3] signals. Parts are sold by maximum processor core frequency; see Section 1.11, “Ordering Information.”

1.5.2.1 Clock AC Specifications

Table 8 provides the clock AC timing specifications as defined in Figure 3.

Table 8. Clock AC Timing Specifications

At recommended operating conditions. See Table 4.

Characteristic	Symbol	Maximum Processor Core Frequency				Unit	Notes
		600 MHz		700 MHz			
		Min	Max	Min	Max		
Processor frequency	f _{core}	500	600	500	700	MHz	1
VCO frequency	f _{VCO}	1000	1200	1000	1400	MHz	1
SYSCLK frequency	f _{SYSCLK}	33	133	33	133	MHz	1
SYSCLK cycle time	t _{SYSCLK}	7.5	30	7.5	30	ns	
SYSCLK rise and fall time	t _{KR} and t _{KF}	—	1.0	—	1.0	ns	2

Table 8. Clock AC Timing Specifications (continued)

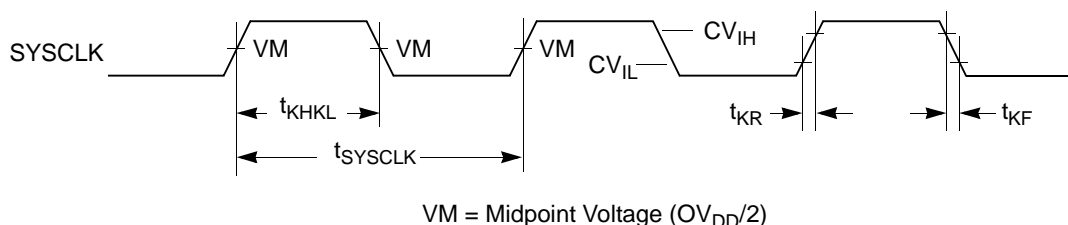
At recommended operating conditions. See Table 4.

Characteristic	Symbol	Maximum Processor Core Frequency				Unit	Notes
		600 MHz		700 MHz			
		Min	Max	Min	Max		
SYSCLK duty cycle measured at OV _{DD} /2	t _{KHKL} /t _{SYSCLK}	40	60	40	60	%	3
SYSCLK jitter		—	±150	—	±150	ps	4, 6
Internal PLL relock time		—	100	—	100	μs	5

Notes:

1. **Caution:** The SYSClk frequency, PLL_EXT and PLL_CFG[0:3] settings must be chosen such that the resulting SYSClk (bus) frequency, CPU (core) frequency, and PLL (VCO) frequency do not exceed their respective maximum or minimum operating frequencies. Refer to the PLL_EXT, PLL_CFG[0:3] signal description in Section 1.9.1, “PLL Configuration,” for valid PLL_EXT and PLL_CFG[0:3] settings.
2. Rise and fall times for the SYSClk input measured from 0.4 V to 1.4 V.
3. Timing is guaranteed by design and characterization.
4. This represents total input jitter—short term and long term combined—and is guaranteed by design.
5. Relock timing is guaranteed by design and characterization. PLL-relock time is the maximum amount of time required for PLL lock after a stable V_{DD} and SYSClk are reached during the power-on reset sequence. This specification also applies when the PLL has been disabled and subsequently re-enabled during sleep mode. Also note that HRESET must be held asserted for a minimum of 255 bus clocks after the PLL-relock time during the power-on reset sequence.
6. The SYSClk driver's closed loop jitter bandwidth should be <500 kHz at –20 dB. The bandwidth must be set low to allow cascade connected PLL-based devices to track SYSClk drivers with the specified jitter.

Figure 3 provides the SYSClk input timing diagram.

**Figure 3. SYSClk Input Timing Diagram**

1.5.2.2 Processor Bus AC Specifications

Table 9 provides the processor bus AC timing specifications for the MPC7441 as defined in Figure 4 and Figure 5.

Table 9. Processor Bus AC Timing Specifications

At recommended operating conditions. See Table 4.

Parameter	Symbol ²	All Speed Grades		Unit	Notes
		Min	Max		
Mode select input setup to $\overline{\text{HRESET}}$	t_{MVRH}	8	—	t_{sysclk}	3, 4, 5, 6
$\overline{\text{HRESET}}$ to mode select input hold	t_{MXRH}	0	—	ns	3, 5
Input setup times: A[0:35], AP[0:4], $\overline{\text{GBL}}$, $\overline{\text{TBST}}$, TSIZ[0:2], $\overline{\text{WT}}$, $\overline{\text{CI}}$, D[0:63], DP[0:7] $\overline{\text{AACK}}$, $\overline{\text{ARTRY}}$, $\overline{\text{BG}}$, $\overline{\text{CKSTP_IN}}$, $\overline{\text{DBG}}$, DTI[0:3], $\overline{\text{HRESET}}$, $\overline{\text{INT}}$, $\overline{\text{MCP}}$, $\overline{\text{QACK}}$, $\overline{\text{SMI}}$, $\overline{\text{SRESET}}$, $\overline{\text{TA}}$, $\overline{\text{TBEN}}$, $\overline{\text{TEA}}$, $\overline{\text{TS}}$, $\overline{\text{EXT_QUAL}}$, $\overline{\text{PMON_IN}}$, $\overline{\text{SHD}}[0:1]$	t_{AVKH} t_{IVKH}	2.0 2.0	— —	ns	
Input hold times: A[0:35], AP[0:4], $\overline{\text{GBL}}$, $\overline{\text{TBST}}$, TSIZ[0:2], $\overline{\text{WT}}$, $\overline{\text{CI}}$, D[0:63], DP[0:7] $\overline{\text{AACK}}$, $\overline{\text{ARTRY}}$, $\overline{\text{BG}}$, $\overline{\text{CKSTP_IN}}$, $\overline{\text{DBG}}$, DTI[0:3], $\overline{\text{HRESET}}$, $\overline{\text{INT}}$, $\overline{\text{MCP}}$, $\overline{\text{QACK}}$, $\overline{\text{SMI}}$, $\overline{\text{SRESET}}$, $\overline{\text{TA}}$, $\overline{\text{TBEN}}$, $\overline{\text{TEA}}$, $\overline{\text{TS}}$, $\overline{\text{EXT_QUAL}}$, $\overline{\text{PMON_IN}}$, $\overline{\text{SHD}}[0:1]$	t_{AXKH} t_{IXKH}	0 0	— —	ns	
Output valid times: A[0:35], AP[0:4], $\overline{\text{GBL}}$, $\overline{\text{TBST}}$, TSIZ[0:2], $\overline{\text{WT}}$, $\overline{\text{CI}}$, $\overline{\text{TS}}$ D[0:63], DP[0:7] $\overline{\text{ARTRY/SHD0/SHD1}}$ $\overline{\text{BR}}$, $\overline{\text{CKSTP_OUT}}$, $\overline{\text{DRDY}}$, $\overline{\text{HIT}}$, $\overline{\text{PMON_OUT}}$, $\overline{\text{QREQ}}$	t_{KHAV} t_{KHTSV} t_{KHdV} t_{KHARV} t_{KHOV}	— — — — —	2.5 2.5 2.5 2.5 2.5	ns	
Output hold times: A[0:35], AP[0:4], $\overline{\text{GBL}}$, $\overline{\text{TBST}}$, TSIZ[0:2], $\overline{\text{WT}}$, $\overline{\text{CI}}$, $\overline{\text{TS}}$ D[0:63], DP[0:7] $\overline{\text{ARTRY/SHD0/SHD1}}$ $\overline{\text{BR}}$, $\overline{\text{CKSTP_OUT}}$, $\overline{\text{DRDY}}$, $\overline{\text{HIT}}$, $\overline{\text{PMON_OUT}}$, $\overline{\text{QREQ}}$	t_{KHAX} t_{KHTSX} t_{KHdX} t_{KHARX} t_{KHOX}	0.5 0.5 0.5 0.5 0.5	— — — — —	ns	
SYSCLK to output enable	t_{KHoe}	0.5	—	ns	
SYSCLK to output high impedance (all except $\overline{\text{TS}}$, $\overline{\text{ARTRY}}$, $\overline{\text{SHD0}}$, $\overline{\text{SHD1}}$)	t_{KHoz}	—	3.5	ns	
SYSCLK to $\overline{\text{TS}}$ high impedance after precharge	t_{KHTSPZ}	—	1	t_{sysclk}	5, 7, 10
Maximum delay to $\overline{\text{ARTRY/SHD0/SHD1}}$ precharge	t_{KHARP}	—	1	t_{sysclk}	5, 8, 9, 10

Table 9. Processor Bus AC Timing Specifications (continued)

At recommended operating conditions. See Table 4.

Parameter	Symbol ²	All Speed Grades		Unit	Notes
		Min	Max		
SYSCLK to $\overline{\text{ARTRY}}/\text{SHD0}/\text{SHD1}$ high impedance after precharge	t_{KHARPZ}	—	2	t_{sysclk}	5, 8, 9, 10

Notes:

1. All input specifications are measured from the midpoint of the signal in question to the midpoint of the rising edge of the input SYSCLK. All output specifications are measured from the midpoint of the rising edge of SYSCLK to the midpoint of the signal in question. All output timings assume a purely resistive 50- Ω load (see Figure 4). Input and output timings are measured at the pin; time-of-flight delays must be added for trace lengths, vias, and connectors in the system.
2. The symbology used for timing specifications herein follows the pattern of $t_{(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{IVKH} symbolizes the time input signals (I) reach the valid state (V) relative to the SYSCLK reference (K) going to the high (H) state or input setup time. And $t_{\text{KH OV}}$ symbolizes the time from SYSCLK(K) going high (H) until outputs (O) are valid (V) or output valid time. Input hold time can be read as the time that the input signal (I) went invalid (X) with respect to the rising clock edge (KH) (note the position of the reference and its state for inputs) and output hold time can be read as the time from the rising edge (KH) until the output went invalid (OX).
3. The setup and hold time is with respect to the rising edge of $\overline{\text{HRESET}}$ (see Figure 5).
4. This specification is for configuration mode select only.
5. t_{sysclk} is the period of the external clock (SYSCLK) in nanoseconds (ns). The numbers given in the table must be multiplied by the period of SYSCLK to compute the actual time duration (in ns) of the parameter in question.
6. Mode select signals are: $\overline{\text{BVSEL}}$, $\text{PLL_CFG}[0:3]$, PLL_EXT , $\text{BMODE}[0:1]$.
7. According to the bus protocol, $\overline{\text{TS}}$ is driven only by the currently active bus master. It is asserted low then precharged high before returning to high impedance as shown in Figure 6. The nominal precharge width for $\overline{\text{TS}}$ is $0.5 \times t_{\text{SYSCLK}}$, i.e., less than the minimum t_{SYSCLK} period, to ensure that another master asserting $\overline{\text{TS}}$ on the following clock will not contend with the precharge. Output valid and output hold timing is tested for the signal asserted. Output valid time is tested for precharge. The high impedance behavior is guaranteed by design.
8. According to the bus protocol, $\overline{\text{ARTRY}}$ can be driven by multiple bus masters through the clock period immediately following $\overline{\text{AACK}}$. Bus contention is not an issue because any master asserting $\overline{\text{ARTRY}}$ will be driving it low. Any master asserting it low in the first clock following $\overline{\text{AACK}}$ will then go to high impedance for one clock before precharging it high during the second cycle after the assertion of $\overline{\text{AACK}}$. The nominal precharge width for $\overline{\text{ARTRY}}$ is $1.0 t_{\text{SYSCLK}}$; that is, it should be high impedance as shown in Figure 6 before the first opportunity for another master to assert $\overline{\text{ARTRY}}$. Output valid and output hold timing is tested for the signal asserted. The high-impedance behavior is guaranteed by design.
9. According to the MPX bus protocol, $\overline{\text{SHD0}}$ and $\overline{\text{SHD1}}$ can be driven by multiple bus masters beginning the cycle of $\overline{\text{TS}}$. Timing is the same as $\overline{\text{ARTRY}}$, i.e., the signal is high impedance for a fraction of a cycle, then negated for up to an entire cycle (crossing a bus cycle boundary) before being three-stated again. The nominal precharge width for $\overline{\text{SHD0}}$ and $\overline{\text{SHD1}}$ is $1.0 t_{\text{SYSCLK}}$. The edges of the precharge vary depending on the programmed ratio of core to bus (PLL configurations).
10. Guaranteed by design and not tested.

Figure 4 provides the AC test load for the MPC7441.

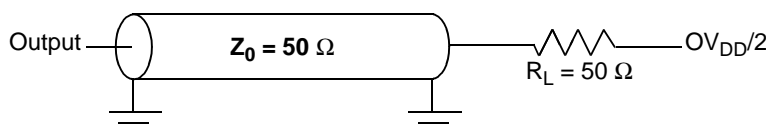
**Figure 4. AC Test Load**

Figure 5 provides the mode select input timing diagram for the MPC7441.

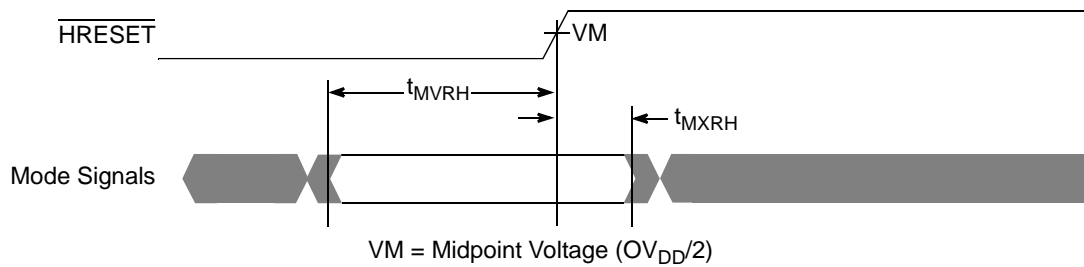


Figure 5. Mode Input Timing Diagram

Figure 6 provides the input/output timing diagram for the MPC7441.

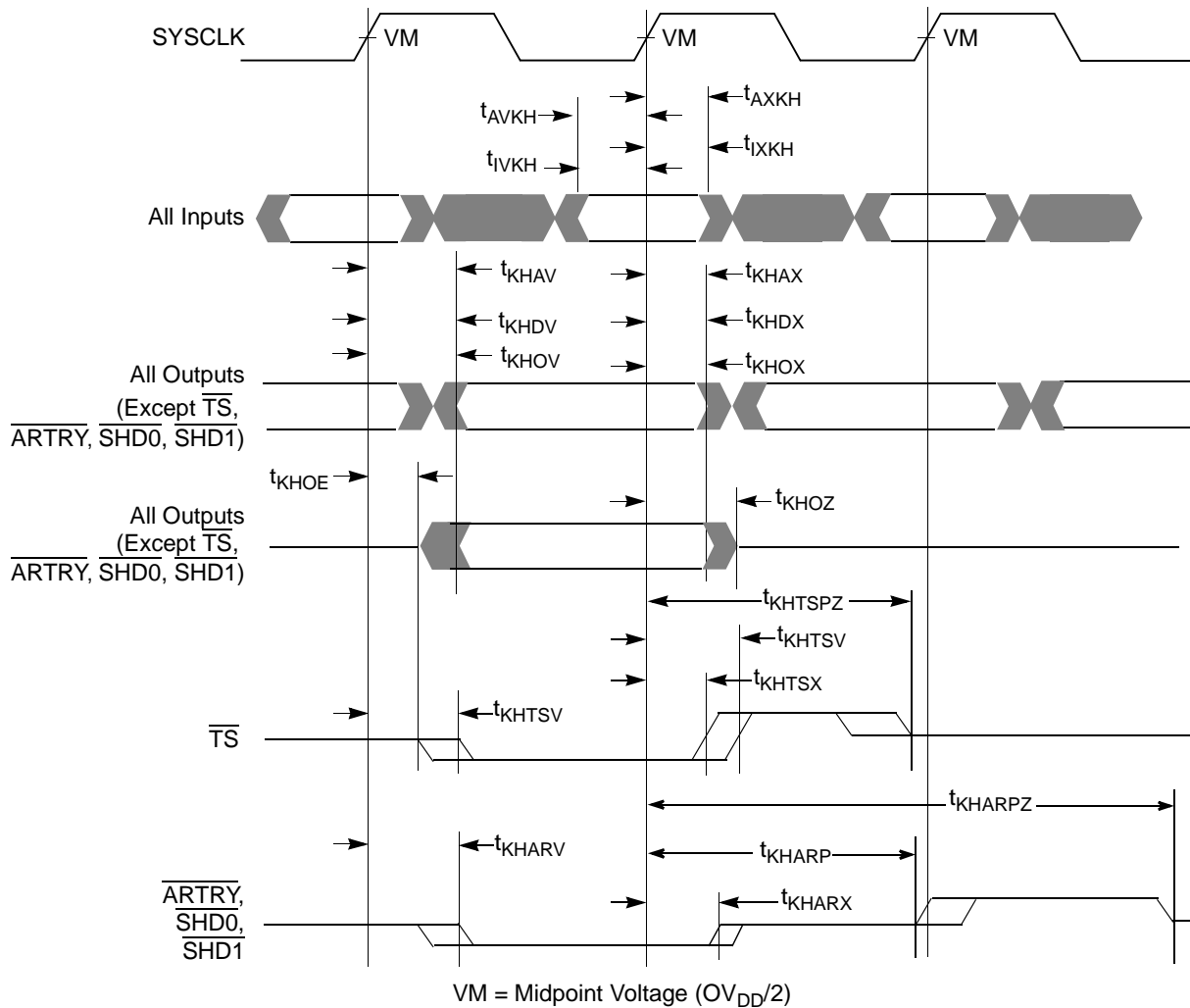


Figure 6. Input/Output Timing Diagram

1.5.2.3 IEEE 1149.1 AC Timing Specifications

Table 10 provides the IEEE 1149.1 (JTAG) AC timing specifications as defined in Figure 8, Figure 9, Figure 10, and Figure 11.

Table 10. JTAG AC Timing Specifications (Independent of SYSCLK)¹

At recommended operating conditions. See Table 4.

Parameter	Symbol	Min	Max	Unit	Notes
TCK frequency of operation	f_{TCLK}	0	33.3	MHz	
TCK cycle time	t_{TCLK}	30	—	ns	
TCK clock pulse width measured at 1.4 V	t_{HJL}	15	—	ns	
TCK rise and fall times	t_{JR} and t_{JF}	0	2	ns	
\overline{TRST} assert time	t_{TRST}	25	—	ns	2
Input setup times: Boundary-scan data TMS, TDI	t_{DVJH} t_{IVJH}	4 0	— —	ns	3
Input hold times: Boundary-scan data TMS, TDI	t_{DXJH} t_{IXJH}	20 25	— —	ns	3
Valid times: Boundary-scan data TDO	t_{JLDV} t_{JLOV}	4 4	20 25	ns	4
Output hold times: Boundary-scan data TDO	t_{JLDX} t_{JLOX}	TBD TBD	TBD TBD	ns	4
TCK to output high impedance: Boundary-scan data TDO	t_{JLDZ} t_{JLOZ}	3 3	19 9	ns	4, 5 5

Notes:

1. All outputs are measured from the midpoint voltage of the falling/rising edge of TCLK to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50- Ω load (see Figure 7). Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.
2. \overline{TRST} is an asynchronous level sensitive signal. The setup time is for test purposes only.
3. Non-JTAG signal input timing with respect to TCK.
4. Non-JTAG signal output timing with respect to TCK.
5. Guaranteed by design and characterization.

Figure 7 provides the AC test load for TDO and the boundary-scan outputs of the MPC7441.

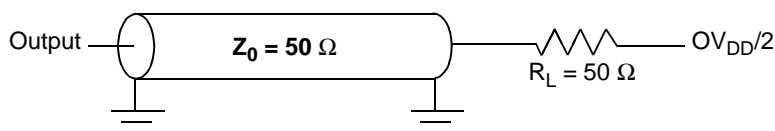


Figure 7. Alternate AC Test Load for the JTAG Interface

Figure 8 provides the JTAG clock input timing diagram.

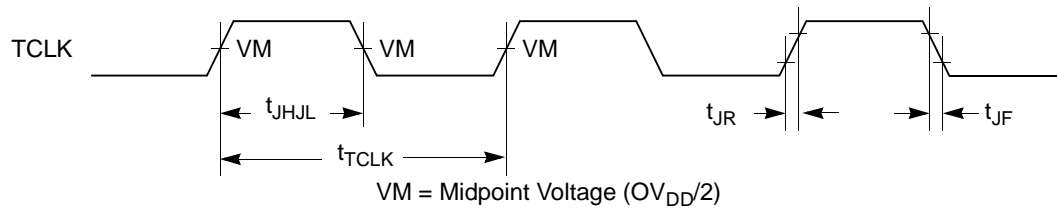


Figure 8. JTAG Clock Input Timing Diagram

Figure 9 provides the $\overline{\text{TRST}}$ timing diagram.

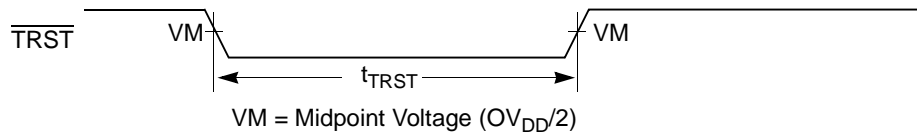


Figure 9. $\overline{\text{TRST}}$ Timing Diagram

Figure 10 provides the boundary-scan timing diagram.

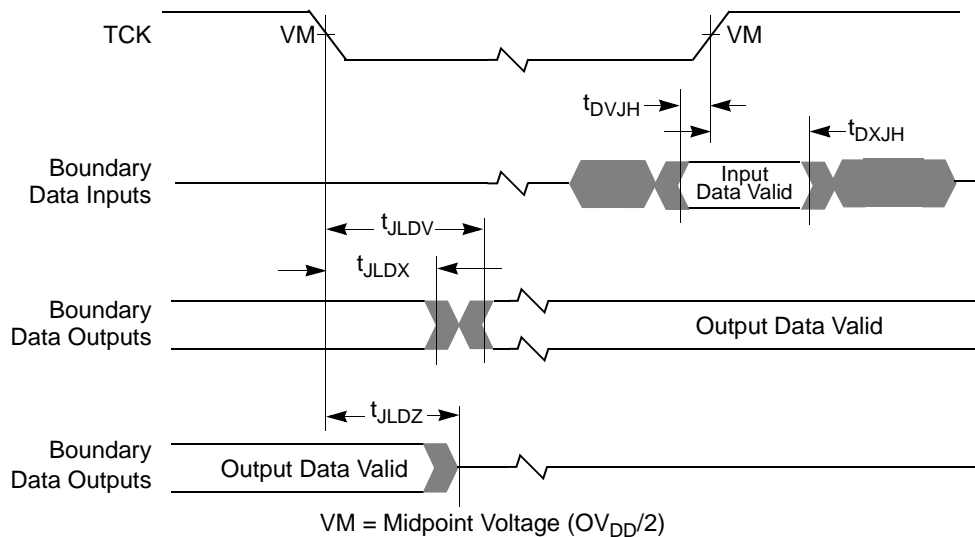


Figure 10. Boundary-Scan Timing Diagram

Electrical and Thermal Characteristics

Figure 11 provides the test access port timing diagram.

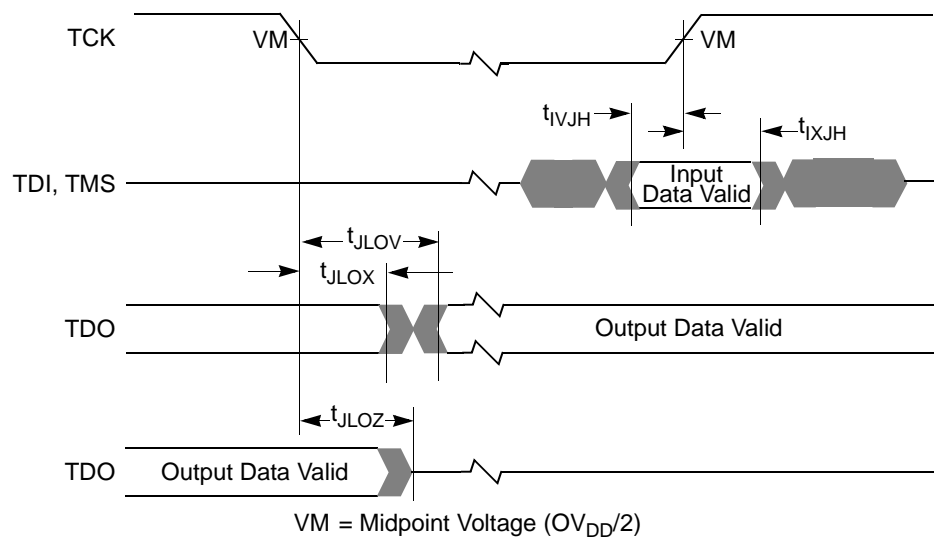
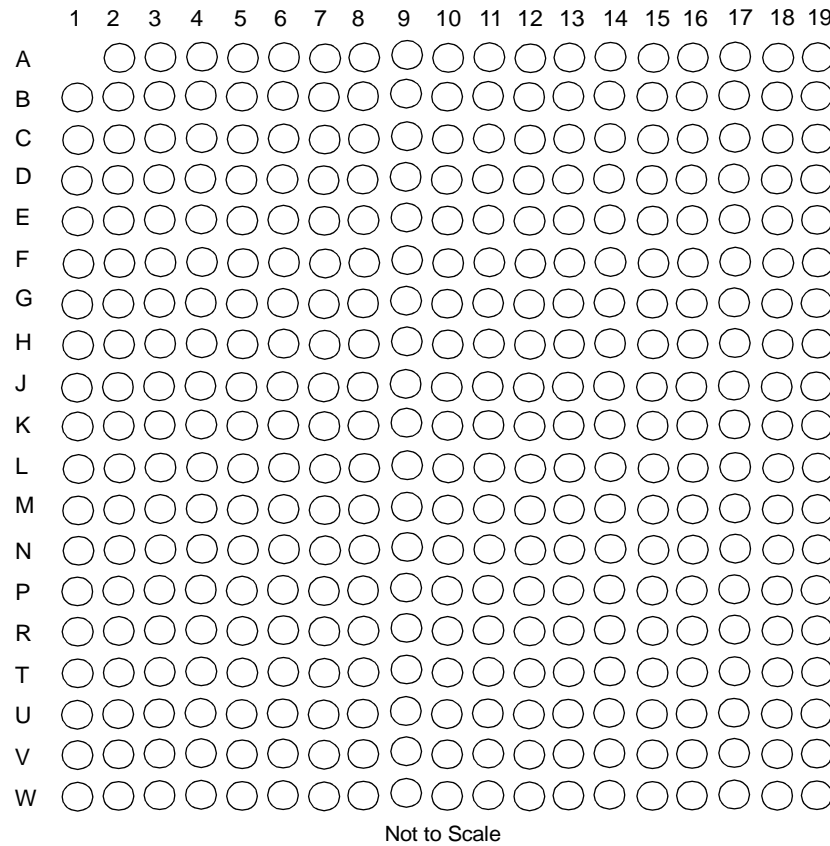


Figure 11. Test Access Port Timing Diagram

1.6 Pin Assignments

Figure 12 (in Part A) shows the pinout of the MPC7441, 360 CBGA package as viewed from the top surface. Part B shows the side profile of the CBGA package to indicate the direction of the top surface view.

Part A



Part B

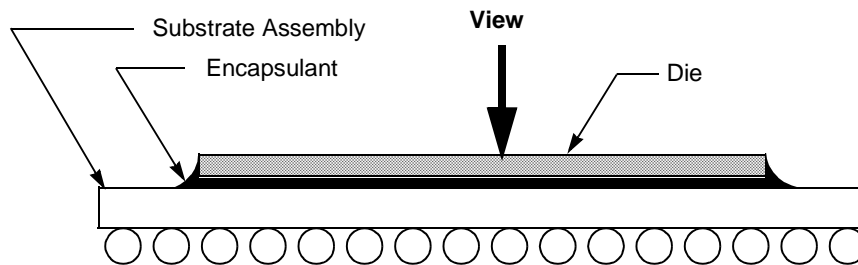


Figure 12. Pinout of the MPC7441, 360 CBGA Package as Viewed from the Top Surface

1.7 Pinout Listings for the 360 CBGA Package

Table 11 provides the pinout listing for the MPC7441, 360 CBGA package.

NOTE

This pinout is not compatible with the MPC750, MPC755, MPC7400, or MPC7410 360 BGA package.

Table 11. Pinout Listing for the MPC7441, 360 CBGA Package

Signal Name	Pin Number	Active	I/O	I/F Select ¹	Notes
A[0:35]	E11, H1, C11, G3, F10, L2, D11, D1, C10, G2, D12, L3, G4, T2, F4, V1, J4, R2, K5, W2, J2, K4, N4, J3, M5, P5, N3, T1, V2, U1, N5, W1, B12, C4, G10, B11	High	I/O	BVSEL	11
$\overline{\text{AACK}}$	R1	Low	Input	BVSEL	
AP[0:4]	C1, E3, H6, F5, G7	High	I/O	BVSEL	
$\overline{\text{ARTRY}}$	N2	Low	I/O	BVSEL	8
AV _{DD}	A8	—	Input	N/A	
$\overline{\text{BG}}$	M1	Low	Input	BVSEL	
$\overline{\text{BMODE0}}$	G9	Low	Input	BVSEL	5
$\overline{\text{BMODE1}}$	F8	Low	Input	BVSEL	6
$\overline{\text{BR}}$	D2	Low	Output	BVSEL	
BVSEL	B7	High	Input	BVSEL	1, 7
$\overline{\text{CI}}$	J1	Low	Output	BVSEL	8
$\overline{\text{CKSTP_IN}}$	A3	Low	Input	BVSEL	
$\overline{\text{CKSTP_OUT}}$	B1	Low	Output	BVSEL	
CLK_OUT	H2	High	Output	BVSEL	
D[0:63]	R15, W15, T14, V16, W16, T15, U15, P14, V13, W13, T13, P13, U14, W14, R12, T12, W12, V12, N11, N10, R11, U11, W11, T11, R10, N9, P10, U10, R9, W10, U9, V9, W5, U6, T5, U5, W7, R6, P7, V6, P17, R19, V18, R18, V19, T19, U19, W19, U18, W17, W18, T16, T18, T17, W3, V17, U4, U8, U7, R7, P6, R8, W8, T8	High	I/O	BVSEL	
$\overline{\text{DBG}}$	M2	Low	Input	BVSEL	
DP[0:7]	T3, W4, T4, W9, M6, V3, N8, W6	High	I/O	BVSEL	
$\overline{\text{DRDY}}$	R3	Low	Output	BVSEL	4
DTI[0:3]	G1, K1, P1, N1	High	Input	BVSEL	4, 13
EXT_QUAL	A11	High	Input	BVSEL	9
$\overline{\text{GBL}}$	E2	Low	I/O	BVSEL	

Table 11. Pinout Listing for the MPC7441, 360 CBGA Package (continued)

Signal Name	Pin Number	Active	I/O	I/F Select ¹	Notes
GND	B5, C3, D6, D13, E17, F3, G17, H4, H7, H9, H11, H13, J6, J8, J10, J12, K7, K3, K9, K11, K13, L6, L8, L10, L12, M4, M7, M9, M11, M13, N7, P3, P9, P12, R5, R14, R17, T7, T10, U3, U13, U17, V5, V8, V11, V15	—	—	N/A	
$\overline{\text{HIT}}$	B2	Low	Output	BVSEL	4
$\overline{\text{HRESET}}$	D8	Low	Input	BVSEL	
$\overline{\text{INT}}$	D4	Low	Input	BVSEL	
L1_TSTCLK	G8	High	Input	BVSEL	9
L2_TSTCLK	B3	High	Input	BVSEL	12
No Connect	A6, A13, A14, A15, A16, A17, A18, A19, B13, B14, B15, B16, B17, B18, B19, C13, C14, C15, C16, C17, C18, C19, D14, D15, D16, D17, D18, D19, E12, E13, E14, E15, E16, E19, F12, F13, F14, F15, F16, F17, F18, F19, G11, G12, G13, G14, G15, G16, G19, H14, H15, H16, H17, H18, H19, J14, J15, J16, J17, J18, J19, K15, K16, K17, K18, K19, L14, L15, L16, L17, L18, L19, M14, M15, M16, M17, M18, M19, N12, N13, N14, N15, N16, N17, N18, N19, P15, P16, P18, P19	—	—	—	3
$\overline{\text{LSSD_MODE}}$	E8	Low	Input	BVSEL	2, 7
$\overline{\text{MCP}}$	C9	Low	Input	BVSEL	
OV _{DD}	B4, C2, C12, D5, E18, F2, G18, H3, J5, K2, L5, M3, N6, P2, P8, P11, R4, R13, R16, T6, T9, U2, U12, U16, V4, V7, V10, V14	—	—	N/A	
PLL_CFG[0:3]	B8, C8, C7, D7	High	Input	BVSEL	
PLL_EXT	A7	High	Input	BVSEL	
$\overline{\text{PMON_IN}}$	D9	Low	Input	BVSEL	10
$\overline{\text{PMON_OUT}}$	A9	Low	Output	BVSEL	
$\overline{\text{QACK}}$	G5	Low	Input	BVSEL	
$\overline{\text{QREQ}}$	P4	Low	Output	BVSEL	
$\overline{\text{SHD}}[0:1]$	E4, H5	Low	I/O	BVSEL	8
$\overline{\text{SMI}}$	F9	Low	Input	BVSEL	
$\overline{\text{SRESET}}$	A2	Low	Input	BVSEL	
SYSCLK	A10	—	Input	BVSEL	
$\overline{\text{TA}}$	K6	Low	Input	BVSEL	
TBEN	E1	High	Input	BVSEL	
$\overline{\text{TBST}}$	F11	Low	Output	BVSEL	
TCK	C6	High	Input	BVSEL	

Table 11. Pinout Listing for the MPC7441, 360 CBGA Package (continued)

Signal Name	Pin Number	Active	I/O	I/F Select ¹	Notes
TDI	B9	High	Input	BVSEL	7
TDO	A4	High	Output	BVSEL	
$\overline{\text{TEA}}$	L1	Low	Input	BVSEL	
TEST[0:3]	A12, B6, B10, E10	—	Input	BVSEL	2
TEST[4]	D10	—	Input	BVSEL	9
TMS	F1	High	Input	BVSEL	7
$\overline{\text{TRST}}$	A5	Low	Input	BVSEL	7, 14
$\overline{\text{TS}}$	L4	Low	I/O	BVSEL	8
TSIZ[0:2]	G6, F7, E7	High	Output	BVSEL	
TT[0:4]	E5, E6, F6, E9, C5	High	I/O	BVSEL	
$\overline{\text{WT}}$	D3	Low	Output	BVSEL	8
V _{DD}	H8, H10, H12, J7, J9, J11, J13, K8, K10, K12, K14, L7, L9, L11, L13, M8, M10, M12	—	—	N/A	

Notes:

1. OV_{DD} supplies power to the processor bus, JTAG, and all control signals; and V_{DD} supplies power to the processor core and the PLL (after filtering to become AV_{DD}). To program the I/O voltage, connect BVSEL to either GND (selects 1.8 V) or to HRESET (selects 2.5 V). If used, the pulldown resistor should be less than 250 Ω . For actual recommended value of V_{in} or supply voltages see Table 4.
2. These input signals are for factory use only and must be pulled up to OV_{DD} for normal machine operation.
3. These signals are for factory use only and must be left unconnected for normal machine operation.
4. Ignored in 60x bus mode.
5. This signal selects between MPX bus mode (asserted) and 60x bus mode (negated) and will be sampled at HRESET going high.
6. This signal must be negated during reset, by pull-up to OV_{DD} or negation by $\overline{\text{HRESET}}$ (inverse of HRESET), to ensure proper operation.
7. Internal pull-up on die.
8. These pins require weak pull-up resistors (for example, 4.7 k Ω) to maintain the control signals in the negated state after they have been actively negated and released by the MPC7441 and other bus masters.
9. These input signals are for factory use only and must be pulled down to GND for normal machine operation.
10. This pin can externally enable the performance monitor counters (PMC) if they are internally enabled by the software. If it will not be used to control the PMC, it should be pulled down to GND so that the software can enable the PMC.
11. Unused address pins must be pulled down to GND.
12. This test signal is recommended to be tied to HRESET; however, other configurations will not adversely affect performance.
13. These signals must be pulled down to GND if unused, or if the MPC7441 is in 60x bus mode.
14. This signal must be asserted during reset, by pull-down to GND or assertion by HRESET, to ensure proper operation.

1.8 Package Description

The following sections provide the package parameters and mechanical dimensions for the CBGA package.

1.8.1 Package Parameters for the MPC7441, 360 CBGA

The package parameters are as provided in the following list. The package type is 25 × 25 mm, 360-lead ceramic ball grid array (CBGA).

Package outline	25 × 25 mm
Interconnects	360 (19 × 19 ball array – 1)
Pitch	1.27 mm (50 mil)
Minimum module height	2.72 mm
Maximum module height	3.24 mm
Ball diameter	0.89 mm (35 mil)

1.8.2 Mechanical Dimensions for the MPC7441, 360 CBGA

Figure 13 provides the mechanical dimensions and bottom surface nomenclature for the MPC7441, 360 CBGA package.

Package Description

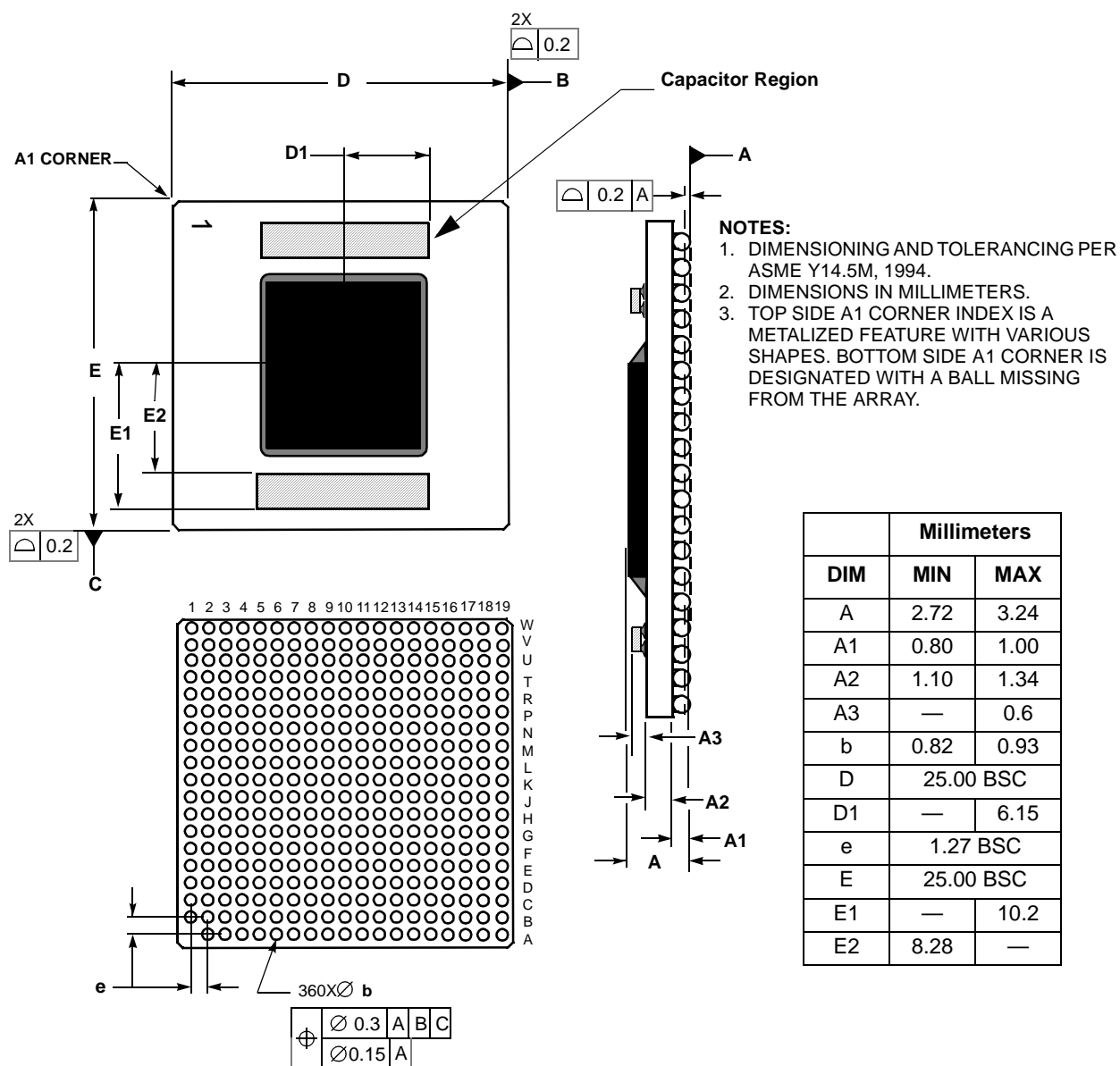


Figure 13. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC7441, 360 CBGA

1.9 System Design Information

This section provides system and thermal design recommendations for successful application of the MPC7441.

1.9.1 PLL Configuration

The MPC7441 PLL is configured by the PLL_EXT and PLL_CFG[0:3] signals. For a given SYSCLK (bus) frequency, the PLL configuration signals set the internal CPU and VCO frequency of operation. PLL_EXT will normally be pulled low but can be asserted for extended modes of operation. The PLL configuration for the MPC7441 is shown in Table 12 for a set of example frequencies. In this example, shaded cells represent settings that, for a given SYSCLK frequency, result in core and/or VCO frequencies that do not comply with the 600-MHz column in Table 8.

Table 12. MPC7441 Microprocessor PLL Configuration Example for 600 MHz Parts

PLL_EXT	PLL_CFG [0:3]	Example Bus-to-Core Frequency in MHz (VCO Frequency in MHz)								
		Bus-to- Core Multiplier	Core-to- VCO Multiplier	Bus 33.3 MHz	Bus 50 MHz	Bus 66.6 MHz	Bus 75 MHz	Bus 83 MHz	Bus 100 MHz	Bus 133 MHz
0	0000	0.5x	2x	16 (33)	25 (50)	33 (66)	37 (75)	47 (83)	50 (100)	66 (133)
0	0100	2x	2x	66 (133)	100 (200)	133 (266)	150 (300)	166 (333)	200 (400)	266 (533)
0	0110	2.5x	2x	83 (166)	125 (250)	166 (333)	187 (375)	208 (415)	250 (500)	333 (666)
0	1000	3x	2x	100 (200)	150 (300)	200 (400)	225 (450)	250 (500)	300 (600)	400 (800)
0	1110	3.5x	2x	116 (233)	175 (350)	233 (466)	262 (525)	291 (581)	350 (700)	466 (933)
0	1010	4x	2x	133 (266)	200 (400)	266 (533)	300 (600)	333 (666)	400 (800)	533 (1066)
0	0111	4.5x	2x	150 (300)	225 (450)	300 (600)	337 (675)	374 (747)	450 (900)	600 (1200)
0	1011	5x	2x	166 (333)	250 (500)	333 (666)	375 (750)	415 (830)	500 (1000)	667 (1333)
0	1001	5.5x	2x	183 (366)	275 (550)	366 (733)	412 (825)	457 (913)	550 (1100)	733 (1466)
0	1101	6x	2x	200 (400)	300 (600)	400 (800)	450 (900)	498 (996)	600 (1200)	
0	0101	6.5x	2x	216 (433)	325 (630)	433 (866)	488 (975)	540 (1080)	650 (1300)	
0	0010	7x	2x	233 (466)	350 (700)	466 (933)	525 (1050)	581 (1162)	700 (1400)	
0	0001	7.5x	2x	250 (500)	375 (750)	500 (1000)	563 (1125)	623 (1245)	750 (1500)	
0	1100	8x	2x	266 (533)	400 (800)	533 (1066)	600 (1200)	664 (1328)		

Table 12. MPC7441 Microprocessor PLL Configuration Example for 600 MHz Parts (continued)

PLL_EXT	PLL_CFG [0:3]	Example Bus-to-Core Frequency in MHz (VCO Frequency in MHz)								
		Bus-to-Core Multiplier	Core-to-VCO Multiplier	Bus 33.3 MHz	Bus 50 MHz	Bus 66.6 MHz	Bus 75 MHz	Bus 83 MHz	Bus 100 MHz	Bus 133 MHz
1	0111	9x	2x	300 (600)	450 (900)	600 (1200)	675 (1350)	747 (1494)		
1	1010	10x	2x	333 (666)	500 (1000)	667 (1333)	750 (1500)			
1	1001	11x	2x	366 (733)	550 (1100)	733 (1466)				
1	1011	12x	2x	400 (800)	600 (1200)					
1	0101	13x	2x	433 (866)	650 (1300)					
1	1100	14x	2x	466 (933)	700 (1400)					
1	0001	15x	2x	500 (1000)	750 (1500)					
1	1101	16x	2x	533 (1066)						
0	0011	PLL off/bypass		PLL off, SYCLK clocks core circuitry directly						
0	1111	PLL off		PLL off, no core clocking occurs						

Notes:

1. PLL_CFG[0:3] settings not listed are reserved.
2. The sample bus-to-core frequencies shown are for reference only. Some PLL configurations may select bus, core, or VCO frequencies which are not useful, not supported, or not tested for by the MPC7441; see Section 1.5.2.1, "Clock AC Specifications," for valid SYCLK, core, and VCO frequencies.
3. In PLL-bypass mode, the SYCLK input signal clocks the internal processor directly and the PLL is disabled. However, the bus interface unit requires a 2x clock to function. Therefore, an additional signal, EXT_QUAL, must be driven at one-half the frequency of SYCLK and offset in phase to meet the required input setup $t_{V_{KH}}$ and hold time $t_{I_{XKH}}$ (see Table 9). The result will be that the processor bus frequency will be one-half SYCLK while the internal processor is clocked at SYCLK frequency. This mode is intended for factory use and emulator tool use only.
Note: The AC timing specifications given in this document do not apply in PLL-bypass mode.
4. In PLL-off mode, no clocking occurs inside the MPC7441 regardless of the SYCLK input.

1.9.2 PLL Power Supply Filtering

The AV_{DD} power signal is provided on the MPC7441 to provide power to the clock generation PLL. To ensure stability of the internal clock, the power supplied to the AV_{DD} input signal should be filtered of any noise in the 500 kHz to 10 MHz resonant frequency range of the PLL. A circuit similar to the one shown in Figure 14 using surface mount capacitors with minimum effective series inductance (ESL) is recommended.

The circuit should be placed as close as possible to the AV_{DD} pin to minimize noise coupled from nearby circuits. It is often possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of the 360 CBGA footprint and very close to the periphery of the 483 CBGA footprint, without the inductance of vias.

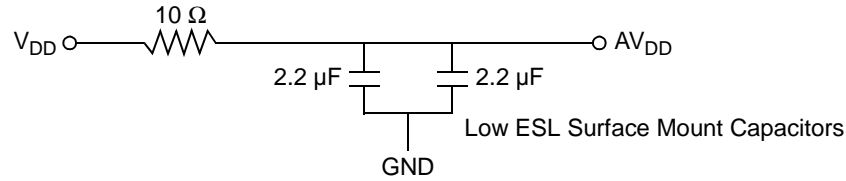


Figure 14. PLL Power Supply Filter Circuit

1.9.3 Power Supply Voltage Sequencing

The notes in Table 2 contain cautions about the sequencing of the external bus voltages and core voltage of the MPC7441 (when they are different). These cautions are necessary for the long-term reliability of the part. If they are violated, the electrostatic discharge (ESD) protection diodes will be forward-biased and excessive current can flow through these diodes. If the system power supply design does not control the voltage sequencing, the circuit shown in Figure 15 can be added to meet these requirements. The 30BF10 diodes (see Figure 15) control the maximum potential difference between the external bus and core power supplies on power-up and the 1N5820 diodes regulate the maximum potential difference on power-down.

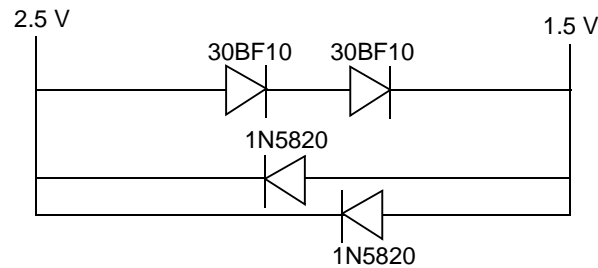


Figure 15. Example Voltage Sequencing Circuit

1.9.4 Decoupling Recommendations

Due to the MPC7441 dynamic power management feature, large address and data buses, and high operating frequencies, the MPC7441 can generate transient power surges and high frequency noise in its power supply, especially while driving large capacitive loads. This noise must be prevented from reaching other components in the MPC7441 system, and the MPC7441 itself requires a clean, tightly regulated source of power. Therefore, it is recommended that the system designer place at least one decoupling capacitor at each V_{DD} and OV_{DD} pin of the MPC7441. It is also recommended that these decoupling capacitors receive their power from separate V_{DD} , OV_{DD} , and GND power planes in the PCB, utilizing short traces to minimize inductance.

These capacitors should have a value of 0.01 μF or 0.1 μF . Only ceramic surface mount technology (SMT) capacitors should be used to minimize lead inductance, preferably 0508 or 0603 orientations where connections are made along the length of the part. Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993) and contrary to previous recommendations for decoupling Motorola microprocessors, multiple small capacitors of equal value are recommended over using multiple values of capacitance.

In addition, it is recommended that there be several bulk storage capacitors distributed around the PCB, feeding the V_{DD} and OV_{DD} planes, to enable quick recharging of the smaller chip capacitors. These bulk capacitors should have a low equivalent series resistance (ESR) rating to ensure the quick response time

necessary. They should also be connected to the power and ground planes through two vias to minimize inductance. Suggested bulk capacitors: 100–330 μF (AVX TPS tantalum or Sanyo OSCON).

1.9.5 Connection Recommendations

To ensure reliable operation, it is highly recommended to connect unused inputs to an appropriate signal level. Unused active low inputs should be tied to OV_{DD} . Unused active high inputs should be connected to GND. All NC (no-connect) signals must remain unconnected.

Power and ground connections must be made to all external V_{DD} , OV_{DD} , and GND pins in the MPC7441.

1.9.6 Output Buffer DC Impedance

The MPC7441 processor bus drivers is characterized over process, voltage, and temperature. To measure Z_0 , an external resistor is connected from the chip pad to OV_{DD} or GND. Then, the value of each resistor is varied until the pad voltage is $\text{OV}_{\text{DD}}/2$ (see Figure 16).

The output impedance is the average of two components, the resistances of the pull-up and pull-down devices. When data is held low, SW2 is closed (SW1 is open), and R_N is trimmed until the voltage at the pad equals $\text{OV}_{\text{DD}}/2$. R_N then becomes the resistance of the pull-down devices. When data is held high, SW1 is closed (SW2 is open), and R_P is trimmed until the voltage at the pad equals $\text{OV}_{\text{DD}}/2$. R_P then becomes the resistance of the pull-up devices. R_P and R_N are designed to be close to each other in value. Then, $Z_0 = (R_P + R_N)/2$.

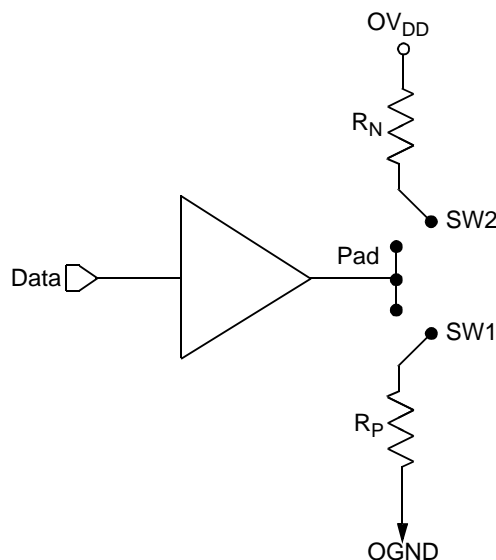


Figure 16. Driver Impedance Measurement

Table 13 summarizes the signal impedance results. The impedance increases with junction temperature and is relatively unaffected by bus voltage.

Table 13. Impedance Characteristics $V_{DD} = 1.5\text{ V}$, $OV_{DD} = 1.8\text{ V} \pm 5\%$, $T_j = 5^\circ\text{--}85^\circ\text{C}$

Impedance		Processor Bus	Unit
Z_0	Typical	33–42	Ω
	Maximum	31–51	Ω

1.9.7 Pull-Up/Pull-Down Resistor Requirements

The MPC7441 requires high-resistive (weak: 4.7 k Ω) pull-up resistors on several control pins of the bus interface to maintain the control signals in the negated state after they have been actively negated and released by the MPC7441 or other bus masters. These pins are: \overline{TS} , \overline{ARTRY} , \overline{SHDO} , and \overline{SHDI} .

Some pins designated as being for factory test must be pulled up to OV_{DD} or down to GND to ensure proper device operation. For the MPC7441, 360 BGA, the pins that must be pulled up to OV_{DD} are: $\overline{LSSD_MODE}$ and $TEST[0:3]$; the pins that must be pulled down to GND are: $L1_TSTCLK$ and $TEST[4]$.

In addition, the MPC7441 has one open-drain style output that requires a pull-up resistor (weak or stronger: 4.7 k Ω –1 k Ω) if it is used by the system. This pin is $\overline{CKSTP_OUT}$.

If a pull-down resistor is used to configure $BVSEL$, the resistor should be less than 250 Ω (see Table 11).

During inactive periods on the bus, the address and transfer attributes may not be driven by any master and may, therefore, float in the high-impedance state for relatively long periods of time. Because the MPC7441 must continually monitor these signals for snooping, this float condition may cause excessive power draw by the input receivers on the MPC7441 or by other receivers in the system. It is recommended that these signals be pulled up through weak (4.7 k Ω) pull-up resistors by the system, or that they may be otherwise driven by the system during inactive periods of the bus. The snooped address and transfer attribute inputs are: $A[0:35]$, $AP[0:4]$, $TT[0:4]$, \overline{CI} , \overline{WT} , and \overline{GBL} .

If extended addressing is not used, $A[0:3]$ are unused and must be pulled low to GND through weak pull-down resistors. If the MPC7441 is in 60x bus mode, $DTI[0:3]$ must be pulled low to GND through weak pull-down resistors.

The data bus input receivers are normally turned off when no read operation is in progress and, therefore, do not require pull-up resistors on the bus. Other data bus receivers in the system, however, may require pull-ups, or that those signals be otherwise driven by the system during inactive periods by the system. The data bus signals are: $D[0:63]$ and $DP[0:7]$.

If address or data parity is not used by the system, and the respective parity checking is disabled through $HID0$, the input receivers for those pins are disabled, and those pins do not require pull-up resistors and should be left unconnected by the system. If all parity generation is disabled through $HID0$, then all parity checking should also be disabled through $HID0$, and all parity pins may be left unconnected by the system.

1.9.8 JTAG Configuration Signals

Boundary scan testing is enabled through the JTAG interface signals. The \overline{TRST} signal is optional in the IEEE 1149.1 specification, but is provided on all processors that implement the PowerPC architecture. While it is possible to force the TAP controller to the reset state using only the TCK and TMS signals, more reliable power-on reset performance will be obtained if the \overline{TRST} signal is asserted during power-on reset. Because the JTAG interface is also used for accessing the common on-chip processor (COP) function, simply tying \overline{TRST} to \overline{HRESET} is not practical.

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The COP function of these processors allows a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP interface connects primarily through the JTAG port of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$ in order to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in Figure 17 allows the COP to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well. An optional pull-down resistor on $\overline{\text{TRST}}$ can be populated to ensure that the JTAG scan chain is initialized during power-on if the JTAG interface and COP header will not be used; otherwise, this resistor should be unpopulated and $\overline{\text{TRST}}$ is asserted when the system reset signal ($\overline{\text{HRESET}}$) is asserted and the JTAG interface is responsible for driving $\overline{\text{TRST}}$ when needed.

The COP header shown in Figure 17 adds many benefits—breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features are possible through this interface—and can be as inexpensive as an unpopulated footprint for a header to be added when needed.

The COP interface has a standard header for connection to the target system, based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

There is no standardized way to number the COP header shown in Figure 17; consequently, many different pin numbers have been observed from emulator vendors. Some are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom, while still others number the pins counter clockwise from pin 1 (as with an IC). Regardless of the numbering, the signal placement recommended in Figure 17 is common to all known emulators.

The $\overline{\text{QACK}}$ signal shown in Figure 17 is usually connected to the PCI bridge chip in a system and is an input to the MPC7441 informing it that it can go into the quiescent state. Under normal operation this occurs during a low-power mode selection. In order for COP to work, the MPC7441 must see this signal asserted (pulled down). While shown on the COP header, not all emulator products drive this signal. If the product does not, a pull-down resistor can be populated to assert this signal. Additionally, some emulator products implement open-drain type outputs and can only drive $\overline{\text{QACK}}$ asserted; for these tools, a pull-up resistor can be implemented to ensure this signal is deasserted when it is not being driven by the tool. Note that the pull-up and pull-down resistors on the $\overline{\text{QACK}}$ signal are mutually exclusive and it is never necessary to populate both in a system. To preserve correct power down operation, $\overline{\text{QACK}}$ should be merged via logic so that it also can be driven by the PCI bridge.

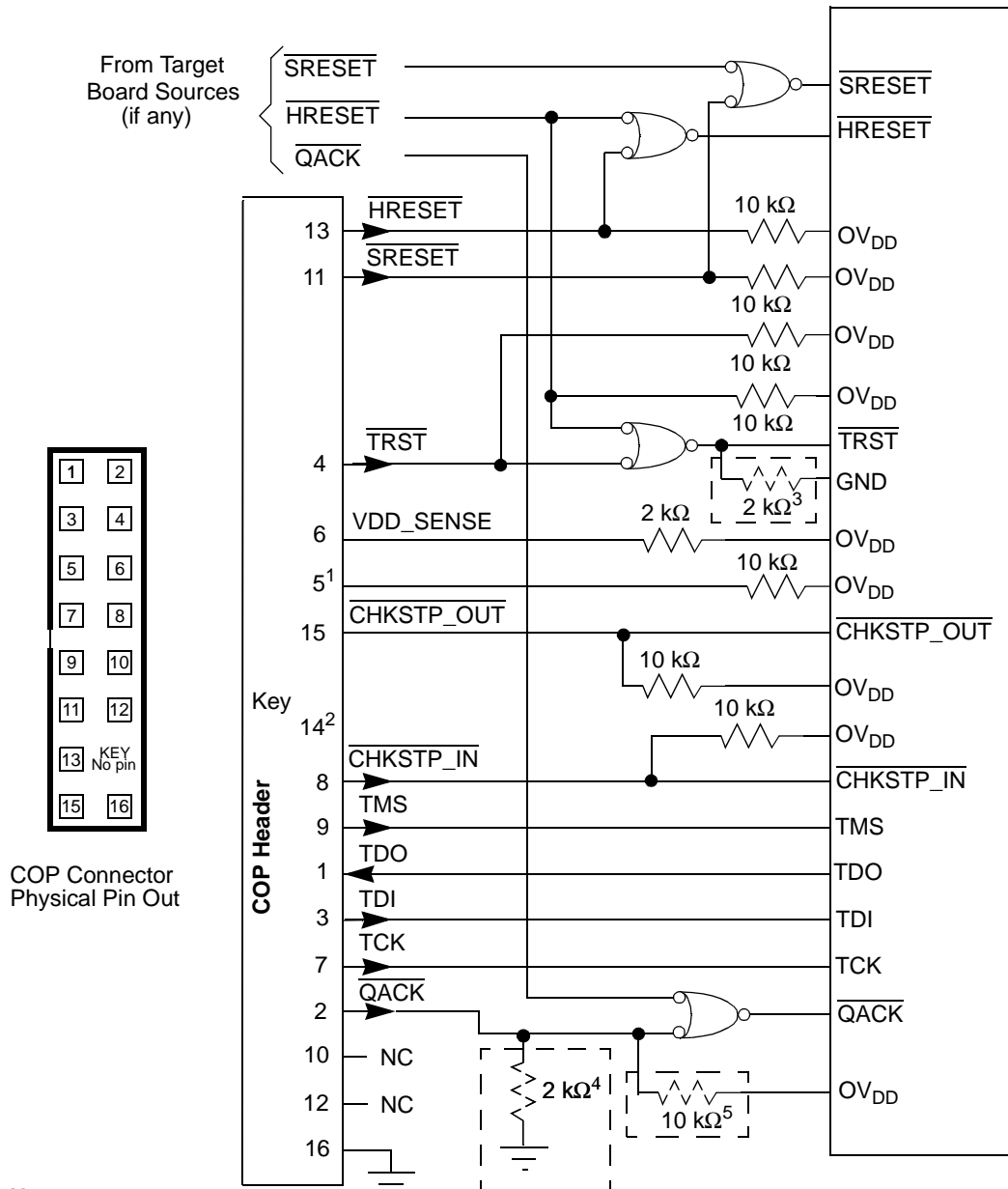


Figure 17. JTAG Interface Connection

1.9.9 Thermal Management Information

This section provides thermal management information for the ceramic ball grid array (CBGA) package for air-cooled applications. Proper thermal control design is primarily dependent on the system-level design—the heat sink, airflow, and thermal interface material. To reduce the die-junction temperature, heat

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sinks may be attached to the package by several methods—spring clip to holes in the printed-circuit board or package, and mounting clip and screw assembly (see Figure 18); however, due to the potential large mass of the heat sink, attachment through the printed circuit board is suggested. If a spring clip is used, the spring force should not exceed 5.5 pounds.

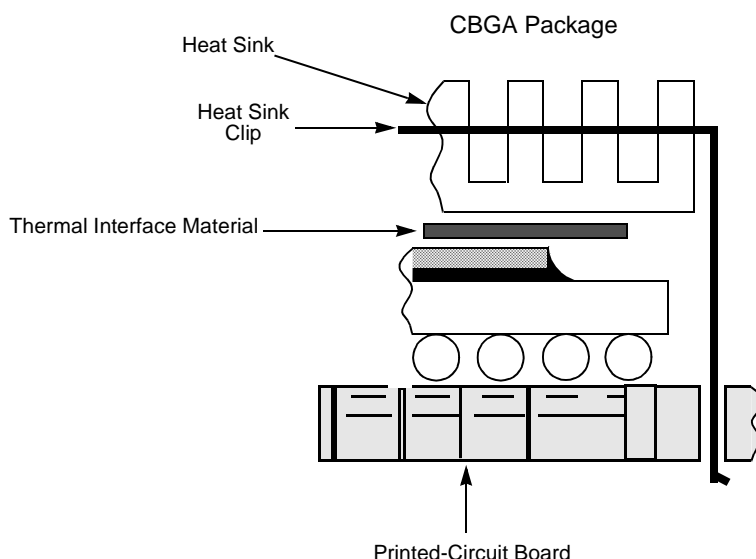


Figure 18. Package Exploded Cross-Sectional View with Several Heat Sink Options

The board designer can choose between several types of heat sinks to place on the MPC7441. There are several commercially available heat sinks for the MPC7441 provided by the following vendors:

Chip Coolers Inc.
333 Strawberry Field Rd.
Warwick, RI 02887-6979
Internet: www.chipcoolers.com

800-227-0254 (USA/Canada)
401-739-7600

International Electronic Research Corporation (IERC) 818-842-7277
135 W. Magnolia Blvd.
Burbank, CA 91502
Internet: www.ctscorp.com

Thermalloy 972-243-4321
2021 W. Valley View Lane
Dallas, TX 75234-8993
Internet: www.thermalloy.com

Wakefield Engineering 781-406-3000
100 Cummings Center, Suite 157H
Beverly, MA 01915
Internet: www.wakefield.com

Aavid Engineering 972-551-7330
250 Apache Trail
Terrell, TX 75160
Internet: www.aavid.com

Cool Innovations Inc.
 260 Spinnaker Way, Unit 8
 Concord, Ontario L4K 4P9
 Canada
 Internet: www.coolinnovations.com

905-760-1992

Ultimately, the final selection of an appropriate heat sink depends on many factors, such as thermal performance at a given air velocity, spatial volume, mass, attachment method, assembly, and cost.

1.9.9.1 Internal Package Conduction Resistance

For the exposed-die packaging technology, shown in Table 3, the intrinsic conduction thermal resistance paths are as follows:

- The die junction-to-case (or top-of-die for exposed silicon) thermal resistance
- The die junction-to-ball thermal resistance

Figure 19 depicts the primary heat transfer path for a package with an attached heat sink mounted to a printed-circuit board.

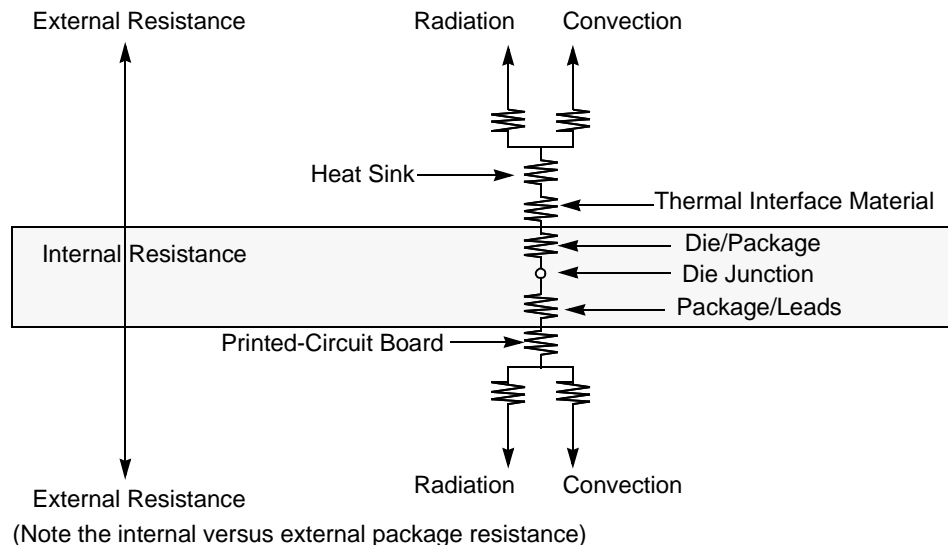


Figure 19. C4 Package with Heat Sink Mounted to a Printed-Circuit Board

Heat generated on the active side of the chip is conducted through the silicon, then through the heat sink attach material (or thermal interface material), and finally to the heat sink where it is removed by forced-air convection.

Because the silicon thermal resistance is quite small, for a first-order analysis, the temperature drop in the silicon may be neglected. Thus, the thermal interface material and the heat sink conduction/convective thermal resistances are the dominant terms.

1.9.9.2 Thermal Interface Materials

A thermal interface material is recommended at the package lid-to-heat sink interface to minimize the thermal contact resistance. For those applications where the heat sink is attached by spring clip mechanism, Figure 20 shows the thermal performance of three thin-sheet thermal-interface materials (silicone,

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graphite/oil, fluoroether oil), a bare joint, and a joint with thermal grease as a function of contact pressure. As shown, the performance of these thermal interface materials improves with increasing contact pressure. The use of thermal grease significantly reduces the interface thermal resistance. That is, the bare joint results in a thermal resistance approximately 7 times greater than the thermal grease joint.

Often, heat sinks are attached to the package by means of a spring clip to holes in the printed-circuit board (see Figure 18). Therefore, the synthetic grease offers the best thermal performance, considering the low interface pressure and is recommended due to the high power dissipation of the MPC7441. Of course, the selection of any thermal interface material depends on many factors—thermal performance requirements, manufacturability, service temperature, dielectric properties, cost, etc.

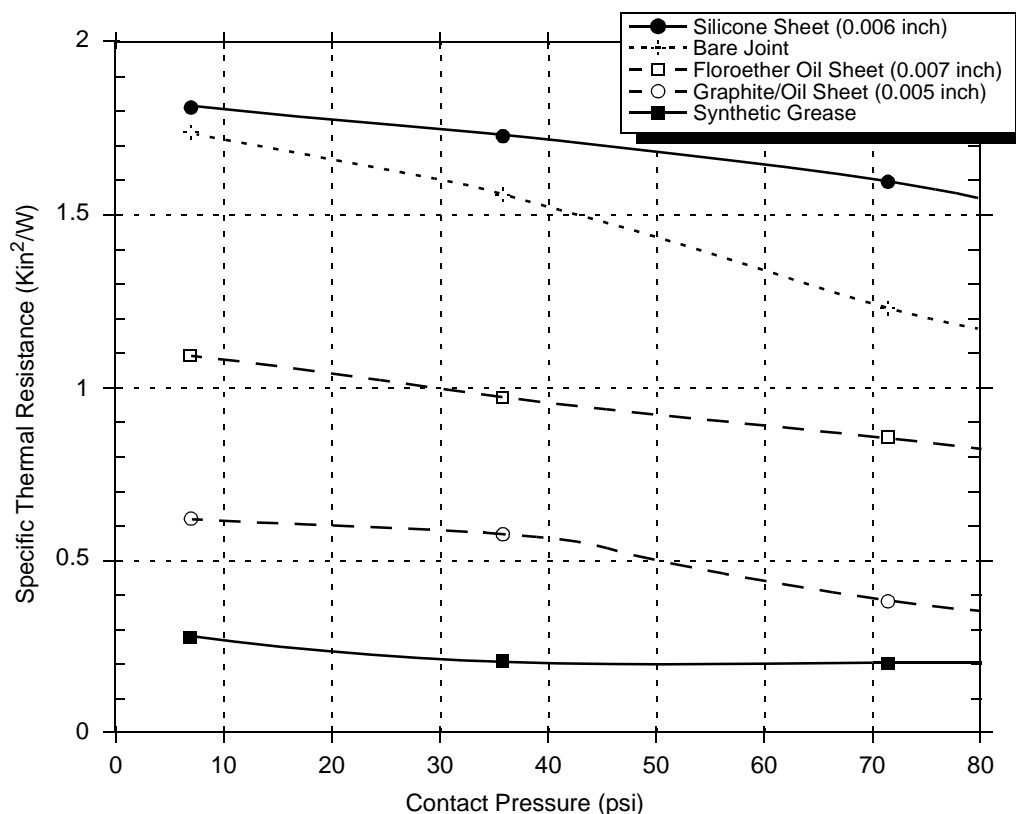


Figure 20. Thermal Performance of Select Thermal Interface Material

The board designer can choose between several types of thermal interface. Heat sink adhesive materials should be selected based upon high conductivity, yet adequate mechanical strength to meet equipment shock/vibration requirements. There are several commercially available thermal interfaces and adhesive materials provided by the following vendors:

Dow-Corning Corporation
Dow-Corning Electronic Materials
PO Box 0997
Midland, MI 48686-0997
Internet: www.dow.com

800-248-2481

Chomerics, Inc.
77 Dragon Court
Woburn, MA 01888-4014
Internet: www.chomerics.com

781-935-4850

Thermagon Inc.
3256 West 25th Street
Cleveland, OH 44109-1668
Internet: www.thermagon.com

888-246-9050

Loctite Corporation
1001 Trout Brook Crossing
Rocky Hill, CT 06067-3910
Internet: www.loctite.com

860-571-5100

The following section provides a heat sink selection example using one of the commercially available heat sinks.

1.9.9.3 Heat Sink Selection Example

For preliminary heat sink sizing, the die-junction temperature can be expressed as follows:

$$T_j = T_a + T_r + (\theta_{jc} + \theta_{int} + \theta_{sa}) \times P_d$$

where:

T_j is the die-junction temperature

T_a is the inlet cabinet ambient temperature

T_r is the air temperature rise within the computer cabinet

θ_{jc} is the junction-to-case thermal resistance

θ_{int} is the adhesive or interface material thermal resistance

θ_{sa} is the heat sink base-to-ambient thermal resistance

P_d is the power dissipated by the device

During operation, the die-junction temperatures (T_j) should be maintained less than the value specified in Table 4. The temperature of the air cooling the component greatly depends upon the ambient inlet air temperature and the air temperature rise within the electronic cabinet. An electronic cabinet inlet-air temperature (T_a) may range from 30° to 40°C. The air temperature rise within a cabinet (T_r) may be in the range of 5° to 10°C. The thermal resistance of the thermal interface material (θ_{int}) is typically about 1.5°C/W. For example, assuming a T_a of 30°C, a T_r of 5°C, a CBGA package $\theta_{jc} = 0.1$, and a typical power consumption (P_d) of 11.5 W, the following expression for T_j is obtained:

$$\text{Die-junction temperature: } T_j = 30^\circ\text{C} + 5^\circ\text{C} + (0.1^\circ\text{C/W} + 1.5^\circ\text{C/W} + \theta_{sa}) \times 11.5 \text{ W}$$

For this example, a θ_{sa} value of 4.4°C/W or less is required to maintain the die junction temperature below the maximum value of Table 4.

Though the die junction-to-ambient and the heat sink-to-ambient thermal resistances are a common figure-of-merit used for comparing the thermal performance of various microelectronic packaging technologies, one should exercise caution when only using this metric in determining thermal management because no single parameter can adequately describe three-dimensional heat flow. The final die-junction operating temperature is not only a function of the component-level thermal resistance, but the system-level design and its operating conditions. In addition to the component's power consumption, a number of factors affect the final operating die-junction temperature—airflow, board population (local heat flux of adjacent components), heat sink efficiency, heat sink attach, heat sink placement, next-level interconnect technology, system air temperature rise, altitude, etc.

Due to the complexity and the many variations of system-level boundary conditions for today's microelectronic equipment, the combined effects of the heat transfer mechanisms (radiation, convection,

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and conduction) may vary widely. For these reasons, we recommend using conjugate heat transfer models for the board, as well as system-level designs.

1.10 Document Revision History

Table 14 provides a revision history for this hardware specification.

Table 14. Document Revision History

Document Revision	Substantive Change(s)
Rev 0	Initial release.

1.11 Ordering Information

Ordering information for the parts fully covered by this specification document is provided in Section 1.11.1, “Part Numbers Fully Addressed by This Document.”

1.11.1 Part Numbers Fully Addressed by This Document

Table 15 provides the Motorola part numbering nomenclature for the MPC7441. Note that the individual part numbers correspond to a maximum processor core frequency. For available frequencies, contact your local Motorola sales office. In addition to the processor frequency, the part numbering scheme also includes an application modifier which may specify special application conditions. Each part number also contains a revision level code which refers to the die mask revision number.

Table 15. Part Numbering Nomenclature

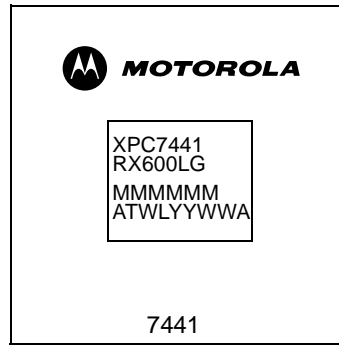
XPC	7441	RX	nnn	x	x
Product Code	Part Identifier	Package	Processor Frequency ¹	Application Modifier	Revision Level
XPC ²	7441	RX = CBGA	600 700	L: 1.5 V ± 50 mV 0 to 105°C	G: 2.3; PVR = 8000 0210

Notes:

1. Processor core frequencies supported by parts addressed by this specification only. Parts addressed by Part Number Specifications may support other maximum core frequencies.
2. The X prefix in a Motorola part number designates a “Pilot Production Prototype” as defined by Motorola SOP 3-13. These are from a limited production volume of prototypes manufactured, tested, and Q.A. inspected on a qualified technology to simulate normal production. These parts have only preliminary reliability and characterization data. Before pilot production prototypes may be shipped, written authorization from the customer must be on file in the applicable sales office acknowledging the qualification status and the fact that product changes may still occur while shipping pilot production prototypes.

1.11.2 Part Marking

Parts are marked as the example shown in Figure 21.



Notes:

BGA

MMMMMM is the 6-digit mask number.

ATWLYYWWA is the traceability code.

CCCCC is the country of assembly. This space is left blank if parts are assembled in the United States.

Figure 21. Part Marking for BGA Device

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81-3-3440-3569

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